

<b>Notice of References Cited</b>	Application/Control No. 10/612,615	Applicant(s)/Patent Under Reexamination INOUE ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0060979	05-2002	Tsukuda et al.	369/275.4
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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